SfW/



PATENT Customer No. 22,852 Attorney Docket No. 04329.3083-00000

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

)								
) Group Art Unit: 2825								
)) Examiner: Belur V. Keshavan								
))								
METHOD OF PURGING) Confirmation No.: 1912 SEMICONDUCTOR) MANUFACTURING APPARATUS) AND METHOD OF) MANUFACTURING) SEMICONDUCTOR DEVICE)								
TRANSMITTAL LETTER								
gust 27, 2004. The items checked below are								
Applicants hereby petition for a months extension of time to respond to the above Office Action. The fee of \$ for the Extension is enclosed.								

_	Claims Remaining After Amendment		Highest Number Previously Paid	Present Extra	Rate	l	tional ee
Total	52	•	32	20	x \$ 18	\$	360
Indep.	4	-	4	0	x \$ 88		0
First	First Presentation of Multiple Dep. Claim(s) +\$300						0
					Subtotal	\$	360
Reduction by ½ if small entity						-	
_		····			TOTAL	\$	360

\boxtimes	A fee of \$ 360.00	to cover the cost of the additional claims added by this reply is
	enclosed.	

 \boxtimes A check for \$ 360.00 to cover the above fee is enclosed.

Please grant any extensions of time required to enter this response and charge any additional required fees to our deposit account 06-0916.

Dated: November 29, 2004

By: Rajeev Gupta
Reg. No. 55,873

PATENT Customer No. 22,852

Attorney Docket No. 04329.3083-00000

HE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2825

Confirmation No.: 1912

Examiner: Belur V. Keshavan

in re Application of:

Ichiro MIZUSHIMA

Application No.: 10/608,020

Filed: June 30, 2003

For: METHOD OF PURGING

SEMICONDUCTOR

MANUFACTURING APPARATUS

AND METHOD OF MANUFACTURING

SEMICONDUCTOR DEVICE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

AMENDMENT

In response to the Office Action of August 27, 2004, with a period for response extending through November 29, 2004 (November 27 being a Saturday), please amend the above-captioned application as follows:

Amendments to the Claims are reflected in the listing of claims beginning at page 2 of this paper.

Remarks are reflected at page 11 of this paper.

Attachments to this Amendment include a copy of Abstract of Watanabe et al.

11/30/2004 EABUBAK1 00000061 10608020

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